

# **Notice of References Cited**

Application/Control No.

09/918,584

Applicant(s)/Patent Under  
Reexamination  
WANG ET AL.

Examiner

Callie E. Shosho

Art Unit

1714

Page 1 of 1

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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